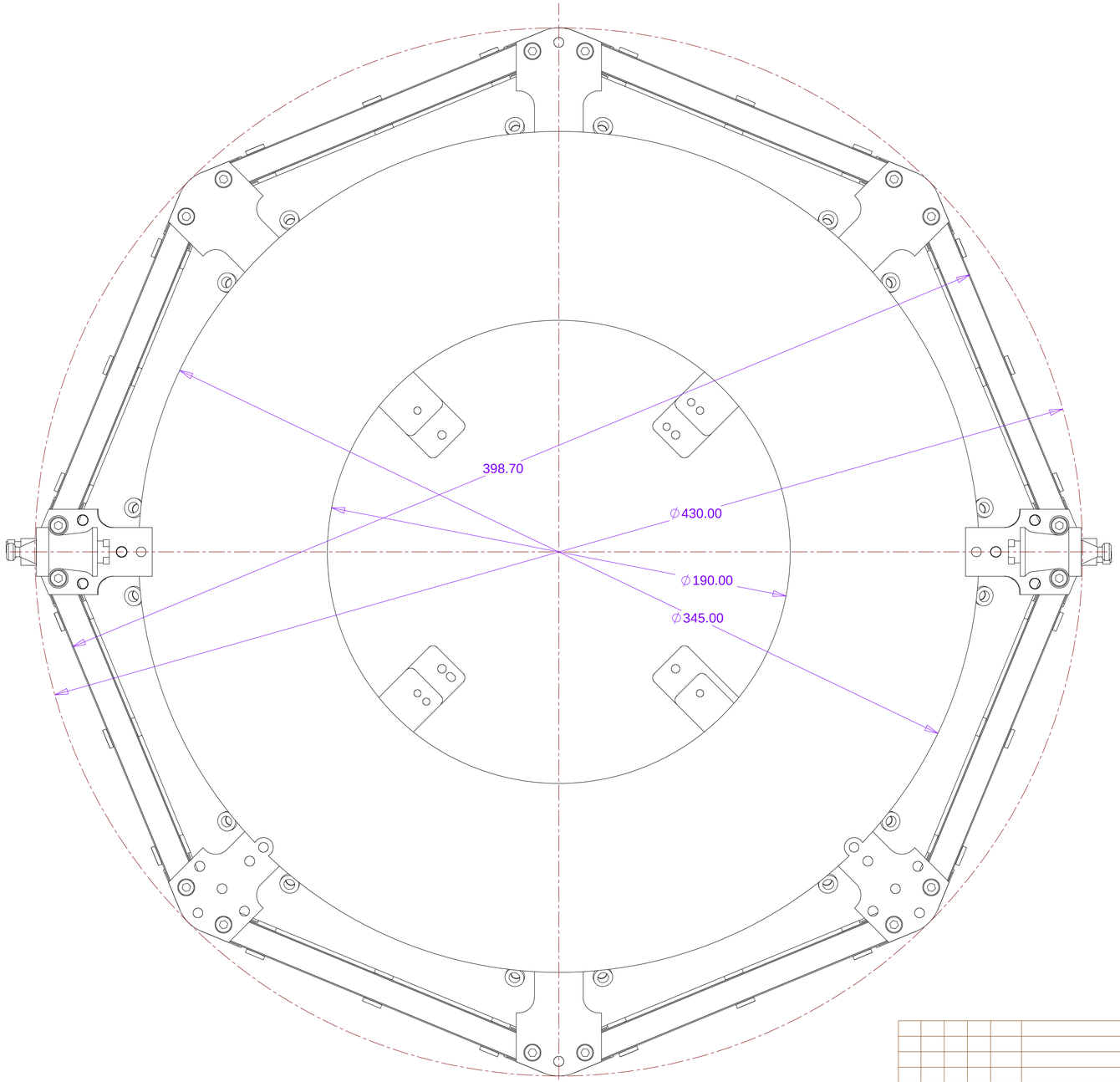
DWG. NO.	SIZE	REV.	SH.
nnXnnn4		1	1

ITEM	PART NO	REQD	DESCRIPTION	MATERIAL



THIRD ANGLE PROJECTION

REV	DWG	CHK	ZONE	DATE	CHANGES

UNLESS OTHERWISE SPECIFIED

TOLERANCES			
X.X ± 0.5	FRAC. ± 1/64		
X.XX ± 0.25	ANGLES ± 30'		
X.XXX ± 0.013	FINISH 1.6		

DO NOT SCALE PRINT

THREADS ARE CLASS 2

CHAMFER ENDS OF ALL SCREW THREADS 30°

CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS

BREAK EDGES .016 MAX. ON MACHINED WORK

REMOVE BURRS, WELD SPLATTER & LOOSE SCALE

IN ACCORDANCE WITH ASME Y14.5m & B46.1

SHOP ORDERS

ACCT NO.		NO. REQD	
DEL TO			
SURFACE TREATMENT			
IDEN METHOD	TAG		
PROJECT NUMBER	ATLIP-ED-0089		
PROJECT NAME	US ATLAS SILICONE SUBSYSTEM		
DWG BY	Roger Smith	DATE	1/29/2003
CHK BY	W.O. Miller	DATE	1/29/2003
APR BY	W.O. Miller	DATE	1/29/2003

SER NO.

DATE ISSD

DATE REQD

US ATLAS SILICON SUBSYSTEM (USSS)

ERNEST ORLANDO LAWRENCE
BERKELEY NATIONAL LABORATORY
UNIVERSITY OF CALIFORNIA - BERKELEY

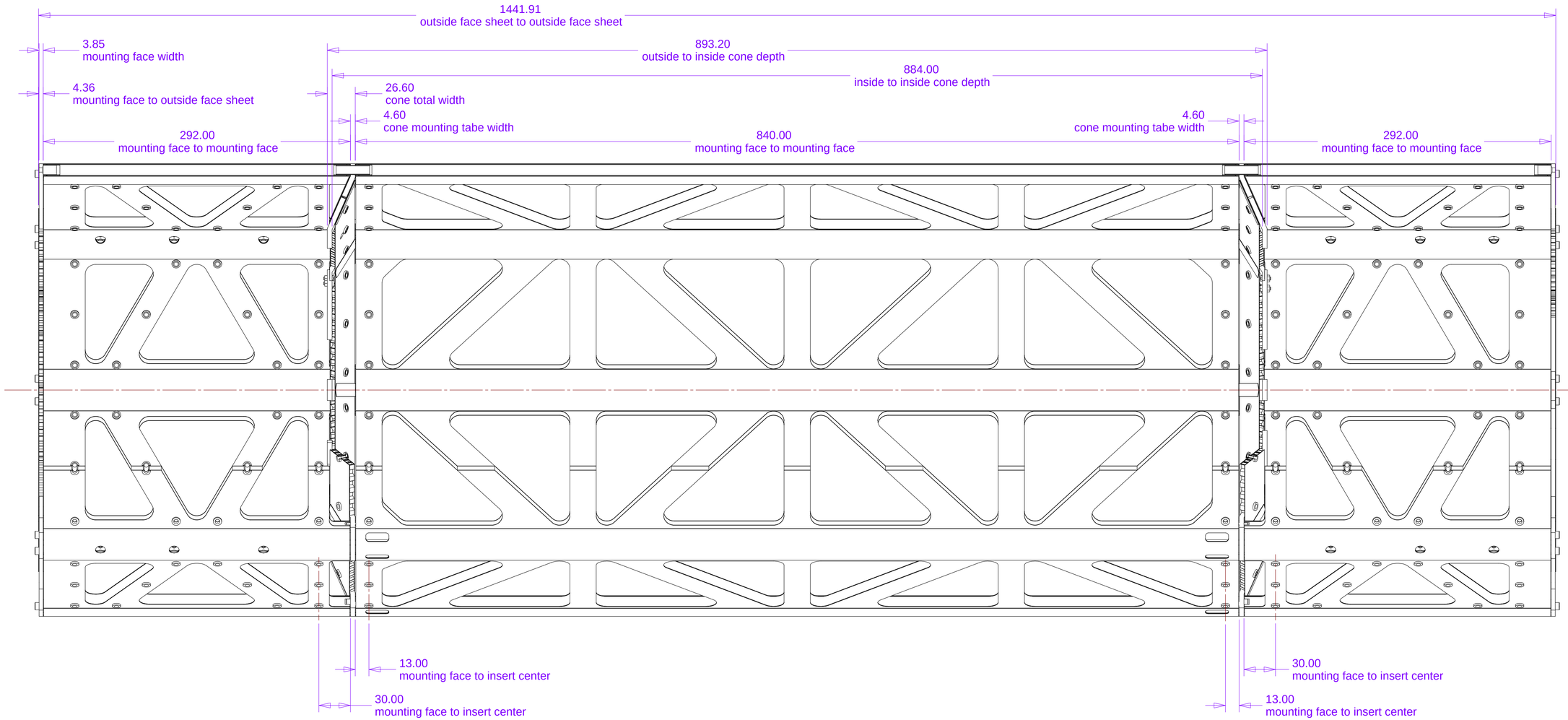
ATLAS PIXEL DETECTOR
8 SIDED FRAME ASSEMBLY
OVERVIEW

MICROFILMED:	DWG. TYPE	SHOWN ON	SCALE: 1:1	DO NOT SCALE PRINTS
	ASSEM	nnXnnn	SHEET 1 OF 3	

PATENT CLEAR:	DESIGN ACCT. NO.	CATEGORY CODE	DWG. NO.	SIZE	REV.
	P1AP-11	AP6250	21F640		1

DWG. NO.	SIZE	REV.	SH.
nnXnnn4		1	2

DESCRIPTION	MATERIAL	MAT. LOCATION



THIRD ANGLE PROJECTION

REV	DWG	CHK	ZONE	DATE	CHANGES

UNLESS OTHERWISE SPECIFIED

TOLERANCES		
	X.X ± 0.5	FRAC. ± 1/64
	X.XX ± 0.25	ANGLES ± 30'
	X.XXX ± 0.013	FINISH 1.6

DO NOT SCALE PRINT

THREADS ARE CLASS 2

CHAMFER ENDS OF ALL SCREW THREADS 30°

CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS

BREAK EDGES .016 MAX. ON MACHINED WORK

REMOVE BURRS, WELD SPLATTER & LOOSE SCALE

IN ACCORDANCE WITH ASME Y14.5m & B46.1

SHOP ORDERS

ACCT NO.		NO. REQD	
DEL TO			
SURFACE TREATMENT			
IDEN METHOD	TAG		
PROJECT NUMBER	ATLP-ED-0089		
PROJECT NAME	US ATLAS SILICONE SUBSYSTEM		
DWG BY	Roger Smith	DATE	1/29/2003
CHK BY	W.O. Miller	DATE	1/29/2003
APR BY	W.O. Miller	DATE	1/29/2003

SER NO.

DATE ISSD

DATE REQD

US ATLAS SILICON SUBSYSTEM (LOGO)

ERNEST ORLANDO LAWRENCE
BERKELEY NATIONAL LABORATORY
UNIVERSITY OF CALIFORNIA - BERKELEY

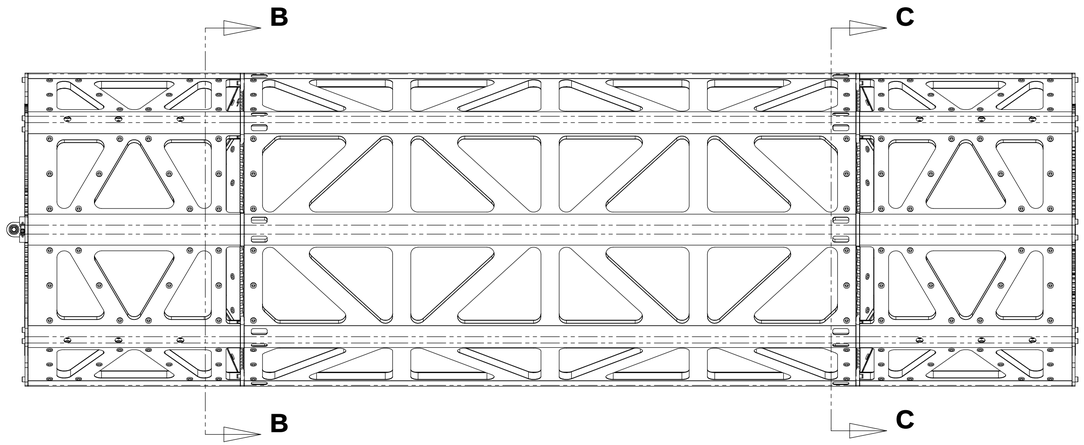
ATLAS PIXEL DETECTOR
8 SIDED FRAME ASSEMBLY
OVERVIEW

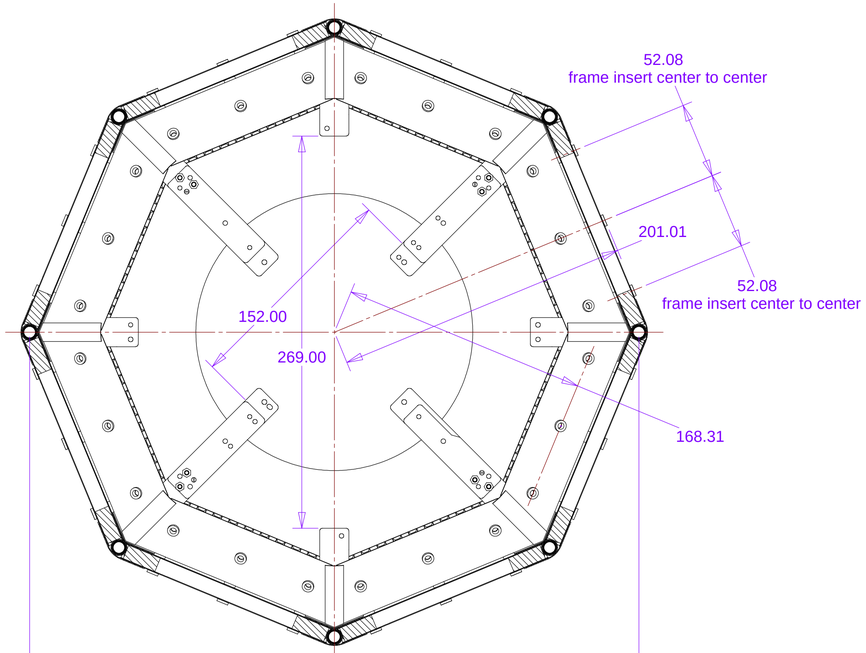
MICROFILMED:	DWG. TYPE	SHOWN ON	SCALE: 1:2	DO NOT SCALE PRINTS
	PART	nnXnnn	SHEET 2 OF 3	

PATENT CLEAR:	DESIGN ACCT. NO.	CATEGORY CIDE	DWG. NO.	SIZE	REV.
	P1AP-11	AP62050	21F640		1

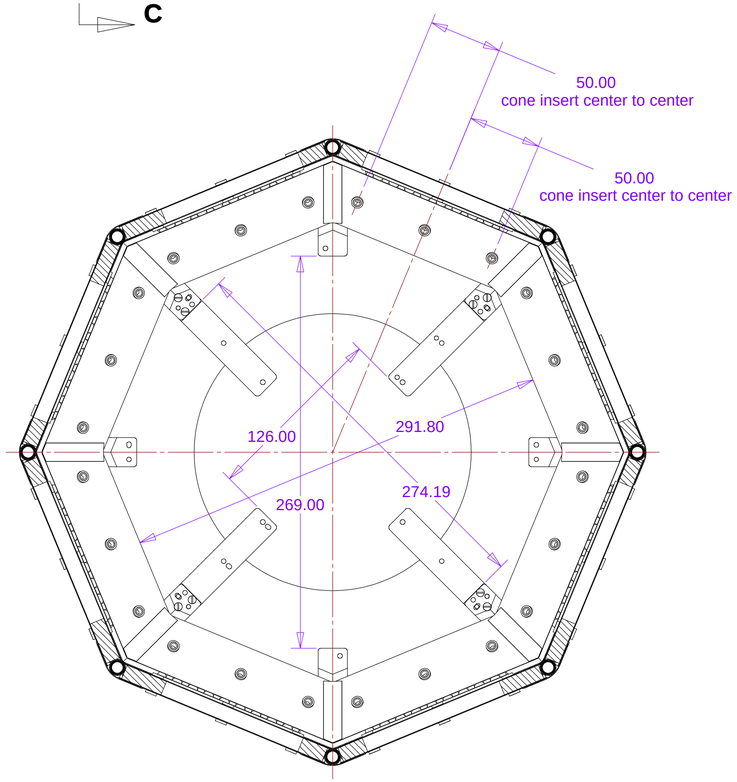
DWG. NO.	SIZE	REV.	SH.
nnXnnn4		1	3

DESCRIPTION	MATERIAL	MAT. LOCATION





SECTION B-B



SECTION C-C

THIRD ANGLE PROJECTION

REV	DWG	CHK	ZONE	DATE	CHANGES

UNLESS OTHERWISE SPECIFIED

TOLERANCES			
	X.X ± 0.5	FRAC. ± 1/64	
	X.XX ± 0.25	ANGLES ± 30'	
	X.XXX ± 0.013	FINISH 1.6	

DO NOT SCALE PRINT

THREADS ARE CLASS 2

CHAMFER ENDS OF ALL SCREW THREADS 30°

CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS

BREAK EDGES .016 MAX. ON MACHINED WORK

REMOVE BURRS, WELD SPLATTER & LOOSE SCALE

IN ACCORDANCE WITH ASME Y14.5m & B46.1

SHOP ORDERS

ACCT NO.		NO. REQD	
DEL TO			
SURFACE TREATMENT			
IDEN METHOD	TAG		
PROJECT NUMBER	ATLIP-ED-0089		
PROJECT NAME	US ATLAS SILICONE SUBSYSTEM		
DWG BY	Roger Smith	DATE	1/29/2003
CHK BY	W.O. Miller	DATE	1/29/2003
APR BY	W.O. Miller	DATE	1/29/2003

SER NO.	
DATE ISSD	
DATE REQD	

US ATLAS SILICON SUBSYSTEM (USSS)

ERNEST ORLANDO LAWRENCE
BERKELEY NATIONAL LABORATORY
UNIVERSITY OF CALIFORNIA - BERKELEY

ATLAS PIXEL DETECTOR
8 SIDED FRAME ASSEMBLY
OVERVIEW

MICROFILMED:	DWG. TYPE	SHOWN ON	SCALE: 1:2	DO NOT SCALE PRINTS
	PART	nnXnnn	SHEET 3 OF 3	
PATENT CLEAR:	DESIGN ACCT. NO.	CATEGORY CIDE	DWG. NO.	SIZE / REV.
	P1AP-11	AP6250	21F640	1